

Measurement

Reality

Simulation

\mathbf{x}_c

*Controllable
Inputs*



True
Process

$y_M(\mathbf{x}_c, \hat{\mathbf{x}}_m)$ Simulator
*"True", but unknown
Model Parameters*



y_T

δ

ϵ_y

*Measurement
Error*

*True
Response*

Model Bias



y_E

Measured
Data